

LTM9012

FEATURES

- 4-Channel Simultaneous Sampling ADC with Integrated, Fixed Gain, Differential Drivers
- 68.3dB SNR
- 78dB SFDR
- Low Power: 1.27W Total, 318mW per Channel
- 1.8V ADC Core and 3.3V Analog Input Supply
- Serial LVDS Outputs: 1 or 2 Bits per Channel
- Shutdown and Nap Modes
- 11.25mm × 15mm BGA Package

APPLICATIONS

- Industrial Imaging
- Medical Imaging
- Multichannel Data Acquisition
- Nondestructive Testing

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Quad 14-Bit, 125Msps ADC with Integrated Drivers

DESCRIPTION

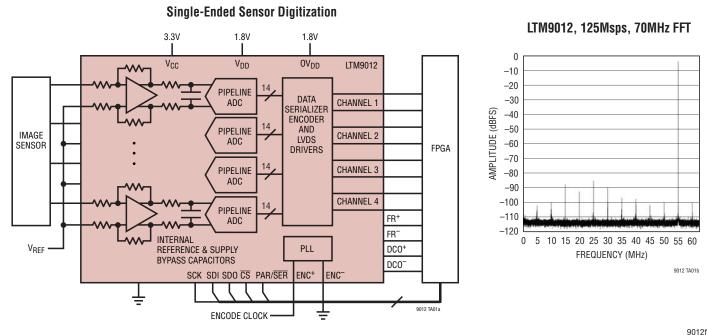
The LTM®9012 is a 4-channel, simultaneous sampling 14-bit μ Module® analog-to-digital converter (ADC) with integrated, fixed gain, differential ADC drivers. The low noise amplifiers are suitable for single-ended drive and pulse train signals such as imaging applications. Each channel includes a lowpass filter between the driver output and ADC input.

DC specs include ± 1.2 LSB INL (typ), ± 0.3 LSB DNL (typ) and no missing codes over temperature. The transition noise is a low 1.2LSB_{RMS}.

The digital outputs are serial LVDS and each channel outputs two bits at a time (2-lane mode). At lower sampling rates there is a one bit option (1-lane mode). The LVDS drivers have optional internal termination and adjustable output levels to ensure clean signal integrity.

The ENC⁺ and ENC⁻ inputs may be driven differentially or single-ended with a sine wave, PECL, LVDS, TTL or CMOS inputs. An internal clock duty cycle stabilizer allows high performance at full speed for a wide range of clock duty cycles.

TYPICAL APPLICATION



LINEAR TECHNOLOGY

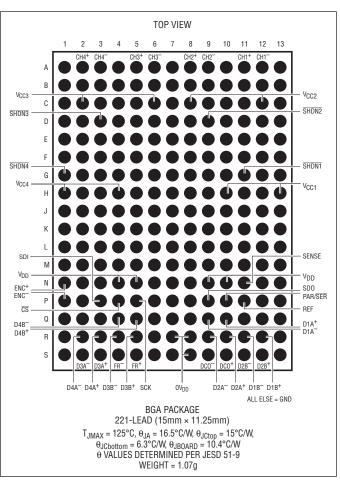
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ABSOLUTE MAXIMUM RATINGS

(Notes 1, 2)

Supply Voltages
V _{DD} , OV _{DD} –0.3V to 2V
V _{CC} –0.3V to 5.5V
Analog Input Voltage (CH <i>n</i> ⁺ , CH <i>n</i> ⁻ , SHDN <i>n</i>)
(Note 3)0.3V to V _{CC}
Analog Input Voltage (PAR/SER, SENSE)
(Note 4) $-0.3V$ to (V _{DD} + 0.2V)
Digital Input Voltage (ENC ⁺ , ENC ⁻ , CS, SDI, SCK)
(Note 5)–0.3V to 3.9V
SDO (Note 5)0.3V to 3.9V
Digital Output Voltage0.3V to (OV _{DD} + 0.3V)
Operating Temperature Range
LTM9012C0°C to 70°C
LTM9012I–40°C to 85°C
Storage Temperature Range65°C to 150°C

PIN CONFIGURATION



ORDER INFORMATION

LEAD FREE FINISH	FREE FINISH TRAY PART MARKING* PACKAGE D		PACKAGE DESCRIPTION	TEMPERATURE RANGE
LTM9012CY-AB#PBF	LTM9012CY-AB#PBF	LTM9012YAB	221-Lead (15mm \times 11.25mm) Plastic BGA	0°C to 70°C
LTM9012IY-AB#PBF	LTM9012IY-AB#PBF	LTM9012YAB	221-Lead (15mm × 11.25mm) Plastic BGA	–40°C to 85°C

Consult LTC Marketing for parts specified with wider operating temperature ranges. *The temperature grade is identified by a label on the shipping container. Consult LTC Marketing for information on non-standard lead based finish parts.

For more information on lead free part marking, go to: http://www.linear.com/leadfree/

This product is only offered in trays. For more information go to: http://www.linear.com/packaging/



CONVERTER CHARACTERISTICS The \bullet denotes the specifications which apply over the full operating temperature range, otherwise specifications are at T_A = 25°C. (Note 6)

PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
Resolution (No Missing Codes)		•	14			Bits
Integral Linearity Error	Differential Analog Input (Note 7)	•	-5	±1.2	5	LSB
Differential Linearity Error	Differential Analog Input	•	-0.9	±0.3	0.9	LSB
Offset Error	(Note 8)	•	-37	±3	37	mV
Gain Error	Internal Reference External Reference	•	-3.6	-1.3 -1.3	3.0	%FS %FS
Offset Drift				±20		μV/°C
Full-Scale Drift	Internal Reference External Reference			±35 ±25		ppm/°C ppm/°C
Gain Matching	External Reference			±0.2		%FS
Offset Matching				±3		mV
Transition Noise	External Reference			1.2		LSB _{RMS}

ANALOG INPUT The \bullet denotes the specifications which apply over the full operating temperature range, otherwise specifications are at T_A = 25°C. (Note 6)

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
V _{IN}	Differential Analog Input Range (CH ⁺ – CH ⁻) at –1dBFS	LTM9012-AB	•		0.2		V _{P-P}
V _{IN(CM)}	Analog Input Common Mode (CH ⁺ + CH ⁻)/2	Differential Analog Input (Note 9)			0 to 1.5		V
V _{SENSE}	External Voltage Reference Applied to SENSE	External Reference Mode	•	0.625	1.250	1.300	V
R _{IN}	Differential Input Resistance	LTM9012-AB			100		Ω
I _{IN(P/S)}	Input Leakage Current	0 < PAR/SER < V _{DD}	•	-3		3	μA
IIN(SENSE)	Input Leakage Current	0.625V < SENSE < 1.3V	•	-6		6	μA
t _{AP}	Sample-and-Hold Acquisition Delay Time				0		ns
t _{JITTER}	Sample-and-Hold Acquisition Delay Jitter				0.15		ps _{RMS}
CMRR	Analog Input Common Mode Rejection Ratio				90		dB
BW-3dB	3dB Corner of Internal Lowpass Filter				90		MHz

DYNAMIC ACCURACY The \bullet denotes the specifications which apply over the full operating temperature range, otherwise specifications are at T_A = 25°C. (Note 6)

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
SNR	Signal-to-Noise Ratio	70MHz Input	•	66.5	68.3		dBFS
SFDR	Spurious Free Dynamic Range 2nd or 3rd Harmonic	70MHz Input	•	66.9	78		dBFS
	Spurious Free Dynamic Range 4th Harmonic or Higher	70MHz Input	•	76.9	86		dBFS
S/N+D	Signal-to-Noise Plus Distortion Ratio	70MHz Input	•	64.7	66.7		dBFS
	Crosstalk, Near Channel	10MHz (Note 12)			70		dBc
	Crosstalk, Far Channel	10MHz (Note 12)			90		dBc



INTERNAL REFERENCE CHARACTERISTICS full operating temperature range, otherwise specifications are at $T_A = 25$ °C.

PARAMETER	CONDITIONS	MIN	ТҮР	MAX	UNITS
V _{REF} Output Voltage	I _{OUT} = 0	1.225	1.250	1.275	V
V _{REF} Output Temperature Drift			±25		ppm/°C
V _{REF} Output Resistance	-400μA < I _{OUT} < 1mA		7		Ω
V _{REF} Line Regulation	1.7V < V _{DD} < 1.9V		0.6		mV/V

DIGITAL INPUTS AND OUTPUTS The \bullet denotes the specifications which apply over the full operating temperature range, otherwise specifications are at T_A = 25°C. (Note 6)

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
ENCODE INF	PUTS (ENC ⁺ , ENC ⁻)			1		I	
Differential	Encode Mode (ENC ⁻ Not Tied to GND)						
VID	Differential Input Voltage	(Note 9)	•	0.2			V
V _{ICM}	Common Mode Input Voltage	Internally Set Externally Set (Note 9)	•	1.1	1.2	1.6	V V
V _{IN}	Input Voltage Range	ENC ⁺ , ENC ⁻ to GND	•	0.2		3.6	V
R _{IN}	Input Resistance	(See Figure 3)			10		kΩ
CIN	Input Capacitance				3.5		pF
Single-Ende	d Encode Mode (ENC ⁻ Tied to GND)		·			· · ·	
VIH	High Level Input Voltage	V _{DD} = 1.8V			1.26		V
V _{IL}	Low Level Input Voltage	V _{DD} = 1.8V		0.54			V
VIN	Input Voltage Range	ENC ⁺ to GND				V	
R _{IN}	Input Resistance	(See Figure 4)			30		kΩ
CIN	Input Capacitance				3.5		pF
Digital Input	ts ($\overline{\textbf{CS}}$, SDI, SCK in Serial or Parallel Progr	amming Mode. SDO in Parallel Programming	Mode)				
V _{IH}	High Level Input Voltage	V _{DD} = 1.8V	•	1.3			V
VIL	Low Level Input Voltage	V _{DD} = 1.8V	•			0.6	V
I _{IN}	Input Current	V _{IN} = 0V to 3.6V	•	-10		10	μA
CIN	Input Capacitance				3		pF
SDO Output	(Serial Programming Mode. Open-Drain O	utput. Requires 2k Pull-Up Resistor if SDO is	Used)				
R _{OH}	Logic Low Output Resistance to GND	V _{DD} = 1.8V, SDO = 0V			200		Ω
I _{OH}	Logic High Output Leakage Current	SDO = 0V to 3.6V	•	-10		10	μA
C _{OUT}	Output Capacitance				3		pF
Digital Input	t (SHDN)						
V _{IH}	High Level Input Voltage	$V_{CC} = 3.3V$	•		0.97	1.4	V
V _{IL}	Low Level Input Voltage	V _{CC} = 3.3V	•	0.6	0.95		V
R _{SHDN}	SHDN Pull-Up Resistor	$V_{\overline{SHDN}} = 0V \text{ to } 0.5V$	•	90	150	210	kΩ
Digital Data	Outputs		·			· · ·	
V _{OD}	Differential Output Voltage	100Ω Differential Load, 3.5mA Mode 100Ω Differential Load, 1.75mA Mode	•	247 125	350 175	454 250	mV mV
V _{0S}	Common Mode Output Voltage	100Ω Differential Load, 3.5mA Mode 100Ω Differential Load, 1.75mA Mode	•	1.125 1.125	1.250 1.250	1.375 1.375	V V
R _{TERM}	On-Chip Termination Resistance	Termination Enabled, OV _{DD} = 1.8V			100		Ω



9012f

POWER REQUIREMENTS The \bullet denotes the specifications which apply over the full operating temperature range, otherwise specifications are at T_A = 25°C. (Note 6)

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
V _{DD}	ADC Supply Voltage	(Note 10)	•	1.7	1.8	1.9	V
OV _{DD}	ADC Output Supply Voltage	(Note 10)	•	1.7	1.8	1.9	V
V _{CC}	Amplifier Supply Voltage	(Note 10)	•	2.7	3.3	3.6	V
I _{VDD}	ADC Supply Current	Sine Wave Input	•		298	320	mA
I _{OVDD}	ADC Output Supply Current	2-Lane Mode, 1.75mA Mode 2-Lane Mode, 3.5mA Mode	•		27 49	31 54	mA mA
IVCC	Amplifier Supply Current		•		208	224	mA
P _{DISS}		2-Lane Mode, 1.75mA Mode 2-Lane Mode, 3.5mA Mode	•		1271 1311	1473 1517	mW mW
P _{SLEEP}					3		mW
P _{NAP}					85		mW
PDIFFCLK	Power Decrease with Single-Ended Encode Mode Enabled				20		mW

TIMING CHARACTERISTICS The \bullet denotes the specifications which apply over the full operating temperature range, otherwise specifications are at T_A = 25°C. (Note 6)

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
f _S	Sampling Frequency	(Note 10, Note 11)		5		125	MHz
t _{ENCL}	ENC Low Time (Note 9)	Duty Cycle Stabilizer Off Duty Cycle Stabilizer On	•	3.8 2	4 4	100 100	ns ns
t _{ENCH}	ENC High Time (Note 9)	Duty Cycle Stabilizer Off Duty Cycle Stabilizer On	•	3.8 2	4	100 100	ns ns
t _{AP}	Sample-and-Hold Acquisition Delay Time				0		ns
Digital Da	ata Outputs ($R_{TERM} = 100\Omega$ [Differential, $C_L = 2pF$ to GND on Each Output)					
t _{SER}	Serial Data Bit Period	2-Lanes, 16-Bit Serialization 2-Lanes, 14-Bit Serialization 2-Lanes, 12-Bit Serialization 1-Lane, 16-Bit Serialization 1-Lane, 14-Bit Serialization 1-Lane, 12-Bit Serialization			$\begin{array}{c} 1/(8 \bullet f_{S}) \\ 1/(7 \bullet f_{S}) \\ 1/(6 \bullet f_{S}) \\ 1/(16 \bullet f_{S}) \\ 1/(14 \bullet f_{S}) \\ 1/(12 \bullet f_{S}) \\ 1/(12 \bullet f_{S}) \end{array}$		SeC SeC SeC SeC SeC SeC
t _{FRAME}	FR to DCO Delay	(Note 9)	•	0.35•t _{SER}	0.5•t _{SER}	0.65•t _{SER}	sec
t _{DATA}	DATA to DCO Delay	(Note 9)	•	0.35•t _{SER}	0.5∙t _{SER}	0.65•t _{SER}	sec
t _{PD}	Propagation Delay	(Note 9)	•	0.7n + 2•t _{SER}	1.1n + 2•t _{SER}	1.5n + 2•t _{SER}	sec
t _R	Output Rise Time	Data, DCO, FR, 20% to 80%			0.17		ns
t _F	Output Fall Time	Data, DCO, FR, 20% to 80%			0.17		ns
	DCO Cycle-Cycle Jitter	t _{SER} = 1ns			60		ps _{P-P}
	Pipeline Latency				6		Cycles
SPI Port 1	Fiming (Note 9)						
t _{SCK}	SCK Period	Write Mode Read Back Mode, C _{SDO} = 20pF, R _{PULLUP} = 2k	•	40 250			ns ns
t _S	CS to SCK Setup Time		•	5			ns
t _H	SCK to CS Setup Time		•	5			ns
t _{DS}	SDI Setup Time		•	5			ns
t _{DH}	SDI Hold Time		•	5			ns
t _{D0}	SCK Falling to SDO Valid	Read Back Mode, C _{SDO} = 20pF, R _{PULLUP} = 2k				125	ns



ELECTRICAL CHARACTERISTICS

Note 1: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. Exposure to any Absolute Maximum Rating condition for extended periods may affect device reliability and lifetime.

Note 2: All voltage values are with respect to GND (unless otherwise noted).

Note 3: Input pins are protected by steering diodes to either supply. If the inputs should exceed either supply voltage, the input current should be limited to less than 10mA. In addition, the inputs CHn^+ , CHn^- are protected by a pair of back-to-back diodes. If the differential input voltage exceeds 1.4V, the input current should be limited to less than 10mA.

Note 4: When these pin voltages are taken below GND or above V_{DD} , they will be clamped by internal diodes. This product can handle input currents greater than 100mA below GND or above V_{DD} without latchup.

Note 5: When these pin voltages are taken below GND they will be clamped by internal diodes. When these pin voltages are taken above V_{DD} they will not be clamped by internal diodes. This product can handle input currents greater than 100mA below GND without latchup.

Note 6: $V_{CC} = 3.3V$, $V_{DD} = 0V_{DD} = 1.8V$, $f_{SAMPLE} = 125MHz$, 2-lane output mode, differential ENC⁺/ENC⁻ = $2V_{P-P}$ sine wave, input range = $200mV_{P-P}$ with differential drive, unless otherwise noted.

Note 7: Integral nonlinearity is defined as the deviation of a code from a best fit straight line to the transfer curve. The deviation is measured from the center of the quantization band.

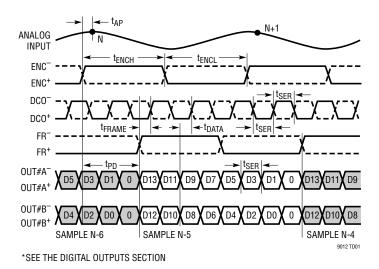
Note 8: Offset error is the offset voltage measured from -0.5 LSB when the output code flickers between 00 0000 0000 0000 and 11 1111 1111 1111 in 2's complement output mode.

Note 9: Guaranteed by design, not subject to test.

Note 10: Recommended operating conditions.

Note 11: The maximum sampling frequency depends on the speed grade of the part and also which serialization mode is used. The maximum serial data rate is 1000Mbps so t_{SER} must be greater than or equal to 1ns. **Note 12:** Near-channel crosstalk refers to CH1 and CH2. Far channel crosstalk refers to CH1 to CH4.

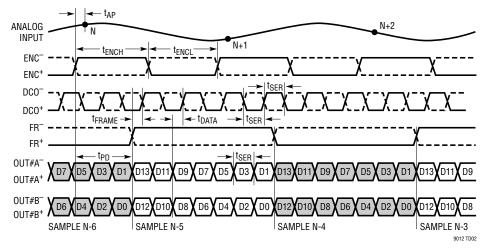
TIMING DIAGRAMS



2-Lane Output Mode, 16-Bit Serialization*



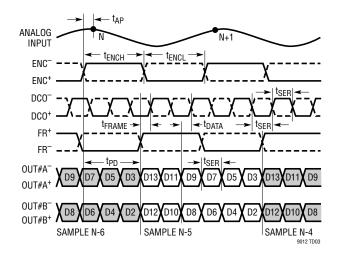
TIMING DIAGRAMS



2-Lane Output Mode, 14-Bit Serialization

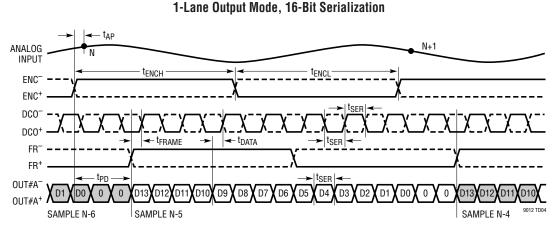
NOTE THAT IN THIS MODE FR⁺/FR⁻ HAS TWO TIMES THE PERIOD OF ENC⁺/ENC⁻

2-Lane Output Mode, 12-Bit Serialization



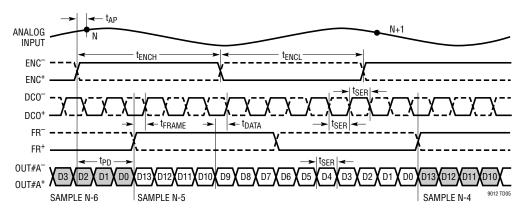


TIMING DIAGRAMS



OUT#B⁺, OUT#B⁻ ARE DISABLED

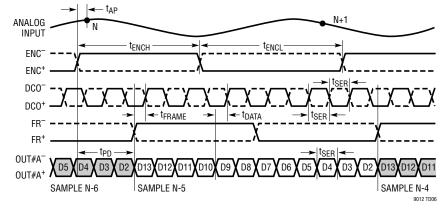




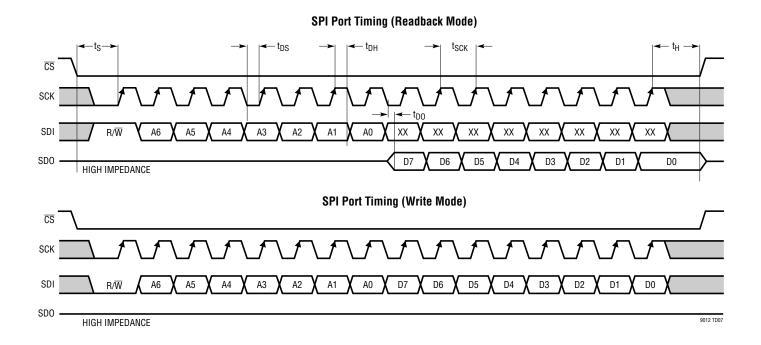
OUT#B⁺, OUT#B⁻ ARE DISABLED



TIMING DIAGRAMS



1-Lane Output Mode, 12-Bit Serialization

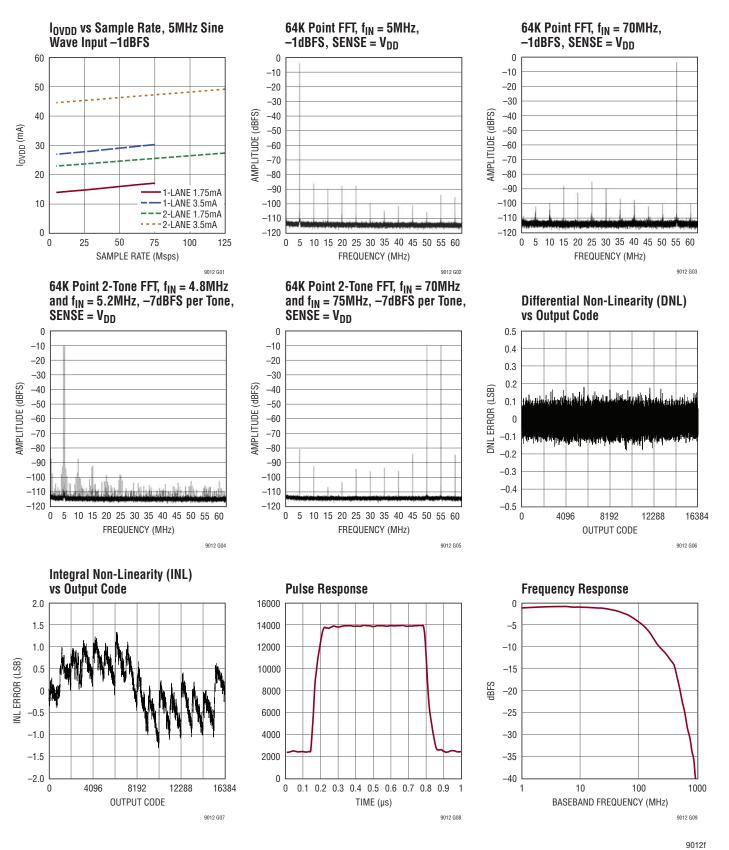




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OUT#B⁺, OUT#B⁻ ARE DISABLED

TYPICAL PERFORMANCE CHARACTERISTICS



PIN FUNCTIONS

 V_{CC1} (H10, H13): Channel 1 Amplifier Supply. V_{CC} is internally bypassed to ground with 0.1μ F in parallel with 0.01μ F ceramic capacitors, additional bypass capacitance is optional. The recommended operating voltage is 3.3V.

 V_{CC2} (C8, C12): Channel 2 Amplifier Supply. V_{CC} is internally bypassed to ground with 0.1μ F in parallel with 0.01μ F ceramic capacitors, additional bypass capacitance is optional. The recommended operating voltage is 3.3V.

 V_{CC3} (C2, C6): Channel 3 Amplifier Supply. V_{CC} is internally bypassed to ground with 0.1μ F in parallel with 0.01μ F ceramic capacitors, additional bypass capacitance is optional. The recommended operating voltage is 3.3V.

 V_{CC4} (H1, H4): Channel 4 Amplifier Supply. V_{CC} is internally bypassed to ground with 0.1µF in parallel with 0.01µF ceramic capacitors, additional bypass capacitance is optional. The recommended operating voltage is 3.3V.

 V_{DD} (N4, N5, N9, N10): ADC Analog Supply. V_{DD} is internally bypassed to ground with 0.1µF ceramic capacitors, additional bypass capacitance is optional. The recommended operating voltage is 1.8V.

 OV_{DD} (R7, R8, S8): ADC Digital Output Supply. OV_{DD} is internally bypassed to ground with 0.1μ F ceramic capacitors, additional bypass capacitance is optional. The recommended operating voltage is 1.8V.

GND: Ground. Use multiple vias close to pins.

CH1⁺ (A11): Channel 1 Noninverting Analog Input.

CH1⁻ (A12): Channel 1 Inverting Analog Input.

CH2⁺ (A8): Channel 2 Noninverting Analog Input.

CH2⁻ (A9): Channel 2 Inverting Analog Input.

CH3⁺ (A5): Channel 3 Noninverting Analog Input.

CH3⁻ (A6): Channel 3 Inverting Analog Input.

CH4+ (A2): Channel 4 Noninverting Analog Input.

CH4⁻ (A3): Channel 4 Inverting Analog Input.

SHDN1 (G11): Channel 1 Amplifier Shutdown. Connecting SHDN1 to V_{CC} or floating results in normal (active) operating mode. Connecting SHDN1 to GND results in a low power shutdown state on amplifier 1.

SHDN2 (D9): Channel 2 Amplifier Shutdown. Connecting SHDN2 to V_{CC} or floating results in normal (active)

operating mode. Connecting SHDN2 to GND results in a low power shutdown state on amplifier 2.

SHDN3 (D3): Channel 3 Amplifier Shutdown. Connecting SHDN3 to V_{CC} or floating results in normal (active) operating mode. Connecting SHDN3 to GND results in a low power shutdown state on amplifier 3.

SHDN4 (G1): Channel 4 Amplifier Shutdown. Connecting SHDN4 to V_{CC} or floating results in normal (active) operating mode. Connecting SHDN4 to GND results in a low power shutdown state on amplifier 4.

ENC⁺ (N1): Encode Input. Conversion starts on the rising edge.

ENC⁻ (P1): Encode Complement Input. Conversion starts on the falling edge.

CS (P4): In serial programming mode, (PAR/SER = 0V), CS is the serial interface chip select input. When CS is low, SCK is enabled for shifting data on SDI into the mode control registers. In the parallel programming mode (PAR/ SER = V_{DD}), CS selects 2-lane or 1-lane output mode. CS can be driven with 1.8V to 3.3V logic.

SCK (P5): In serial programming mode, (PAR/SER = 0V), SCK is the serial interface clock input. In the parallel programming mode (PAR/SER = V_{DD}), SCK selects 3.5mA or 1.75mA LVDS output currents. SCK can be driven with 1.8V to 3.3V logic.

SDI (P3): In serial programming mode, (PAR/ $\overline{SER} = 0V$), SDI is the serial interface data Input. Data on SDI is clocked into the mode control registers on the rising edge of SCK. In the parallel programming mode (PAR/ $\overline{SER} = V_{DD}$), SDI can be used to power down the part. SDI can be driven with 1.8V to 3.3V logic.

SDO (P9): In serial programming mode, (PAR/SER = 0V), SDO is the optional serial interface data output. Data on SDO is read back from the mode control registers and can be latched on the falling edge of SCK. SDO is an opendrain NMOS output that requires an external 2k pull-up resistor to 1.8V - 3.3V. If read back from the mode control registers is not needed, the pull-up resistor is not necessary and SDO can be left unconnected. In the parallel programming mode (PAR/SER = V_{DD}), SDO is an input that enables internal 100Ω termination resistors. When used as an input, SDO can be driven with 1.8V to 3.3V logic through a 1k series resistor.



PIN FUNCTIONS

PAR/SER (P10): Programming Mode Selection Pin. Connect to ground to enable the serial programming mode. \overline{CS} , SCK, SDI and SDO become a serial interface that controls the A/D operating modes. Connect to V_{DD} to enable the parallel programming mode where \overline{CS} , SCK, SDI and SDO become parallel logic inputs that control a reduced set of the A/D operating modes. PAR/SER should be connected directly to ground or the V_{DD} of the part and not be driven by a logic signal.

V_{REF} (P11): Reference Voltage Output. V_{REF} is internally bypassed to ground with a 2.2µF ceramic capacitor, nominally 1.25V.

SENSE (N11): Reference Programming Pin. Connecting SENSE to V_{DD} selects the internal reference and a $\pm 0.1V$ input range. Connecting SENSE to ground selects the internal reference and a $\pm 0.05V$ input range. An external reference between 0.625V and 1.3V applied to SENSE selects an input range of $\pm 0.08 \cdot V_{SENSE}$. SENSE is internally bypassed to ground with a 0.1µF ceramic capacitor.

LVDS Outputs

All pins in this section are differential LVDS outputs. The output current level is programmable. There is an optional internal 100Ω termination resistor between the pins of each LVDS output pair.

OUT1A⁻/OUT1A⁺, OUT1B⁻/OUT1B⁺ (Q9/Q10, R11/R12): Serial data outputs for Channel 1. In 1-lane output mode only OUT1A⁻/OUT1A⁺ are used.

OUT2A⁻/OUT2A⁺, OUT2B⁻/OUT2B⁺ (R9/R10, S11/S12): Serial data outputs for Channel 2. In 1-lane output mode only OUT2A⁻/OUT2A⁺ are used.

OUT3A⁻/OUT3A⁺, OUT3B⁻/OUT3B⁺ (S2/S3, R4/R5): Serial data outputs for Channel 3. In 1-lane output mode only OUT3A⁻/OUT3A⁺ are used.

OUT4A⁻/OUT4A⁺, OUT4B⁻/OUT4B⁺ (R2/R3, Q4/Q5): Serial data outputs for Channel 4. In 1-lane output mode only OUT4A⁻/OUT4A⁺ are used.

FR⁻/FR⁺ (S4/S5): Frame Start Output.

DCO⁻/DCO⁺ (S9/S10): Data Clock Output.

PIN CONFIGURATION TABLE	PIN	CONFIG	URATION	TABLE
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	1	2	3	4	5	6	7	8	9	10	11	12	13
A	GND	CH4 ⁺	CH4 ⁻	GND	CH3+	CH3 ⁻	GND	CH2+	CH2 ⁻	GND	CH1+	CH1 ⁻	GND
B	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND
C	GND	V _{CC3}	GND	GND	GND	V _{CC3}	GND	V _{CC2}	GND	GND	GND	V _{CC2}	GND
D	GND	GND	SHDN3	GND	GND	GND	GND	GND	SHDN2	GND	GND	GND	GND
E	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND
F	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND
G	SHDN4	GND	GND	GND	GND	GND	GND	GND	GND	GND	SHDN1	GND	GND
H	V _{CC4}	GND	GND	V _{CC4}	GND	GND	GND	GND	GND	V _{CC1}	GND	GND	V _{CC1}
J	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND
K	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND
L	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND
М	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND
N	ENC ⁺	GND	GND	V _{DD}	V _{DD}	GND	GND	GND	V _{DD}	V _{DD}	SENSE	GND	GND
P	ENC-	GND	SDI	CS	SCK	GND	GND	GND	SDO	PAR/SER	REF	GND	GND
Q	GND	GND	GND	D4B-	D4B+	GND	GND	GND	D1A ⁻	D1A+	GND	GND	GND
R	GND	D4A ⁻	D4A ⁺	D3B-	D3B ⁺	GND	OVDD	OVDD	D2A ⁻	D2A ⁺	D1B ⁻	D1B ⁺	GND
S	GND	D3A-	D3A+	FR ⁻	FR+	GND	GND	OVDD	DCO-	DCO+	D2B ⁻	D2B ⁺	GND



BLOCK DIAGRAM

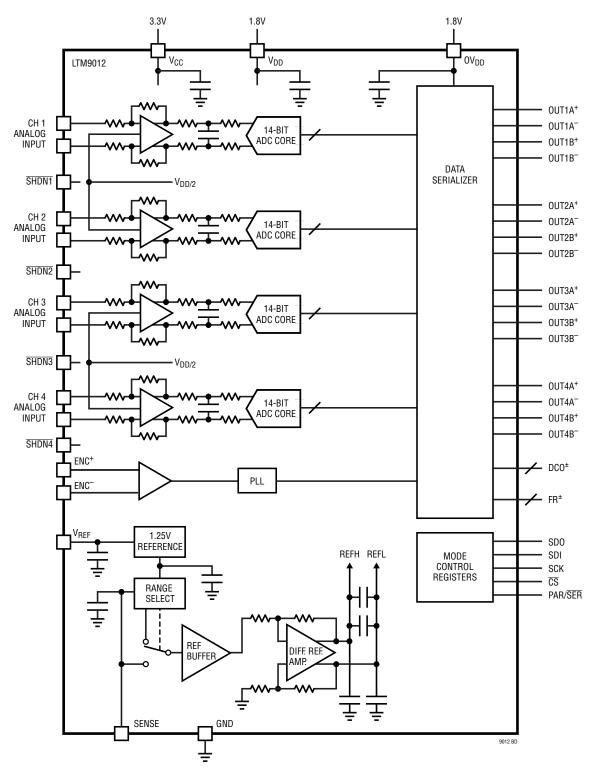


Figure 1. Block Diagram



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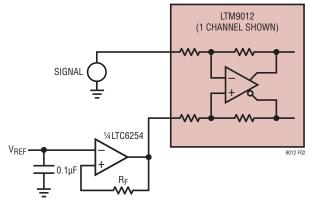
CONVERTER OPERATION

The LTM9012 is a low power, 4-channel, 14-bit, 125Msps A/D converter that is powered by a 1.8V ADC supply and 3.3V driver supplies. Each input includes a fixed gain, differential amplifier. The analog inputs can be driven differentially or single-ended. The encode input can be driven differentially for optimal jitter performance, or single-ended for lower power consumption. The digital outputs are serial LVDS to minimize the number of data lines. Each channel outputs two bits at a time (2-lane mode). At lower sampling rates there is a one bit per channel option (1-lane mode). Many additional features can be chosen by programming the mode control registers through a serial SPI port.

Analog Inputs

The analog inputs for each channel of the LTM9012 consist of a differential amplifier with fixed gain followed by a lowpass filter. The 10x gain version has 49.9Ω series resistance in each input.

The differential input can support single-ended operation by connecting the inverting input to a fixed DC voltage or ground. However, if ground is used, there will be a 6dB loss of dynamic range. For maximum dynamic range, connect the inverting inputs of the LTM9012 to a DC voltage equal to the median of the voltage excursions of the noninverting input. An op amp provides an excellent means of providing a low impedance voltage source capable of sourcing and sinking small amounts of current. Note the value of this DC voltage should fall between the limits of allowable input common mode voltages. See Figure 2 for an example.



SET V_{REF} EQUAL TO THE DC MEDIAN OF THE SIGNAL VOLTAGE

Figure 2. Single-Ended Operation

The gain of the LTM9012 may also be decreased from the nominal value by adding resistance in series with the signal inputs. The internal op amps are fed by 49.9Ω series resistors and employ 511Ω feedback resistors. The voltage gain of the stage is set by the ratio of the feedback resistance to the total series resistance. Unity gain, for example, can be realized by adding a 464Ω resistor in series with each input.

Reference

The LTM9012 has an internal 1.25V voltage reference. For a 2V input range using the internal reference with a unity gain internal amplifier configuration, connect SENSE to V_{DD} . For a 1V input range using the internal reference, connect SENSE to ground. For a 2V input range with an external reference, apply a 1.25V reference voltage to SENSE.

The input range can be adjusted by applying a voltage to SENSE that is between 0.625V and 1.30V. The input range will then be 1.6 • V_{SENSE} .

The reference is shared by all four ADC channels, so it is not possible to independently adjust the input range of individual channels.



Encode Input

The signal quality of the encode inputs strongly affects the A/D noise performance. The encode inputs should be treated as analog signals—do not route them next to digital traces on the circuit board. There are two modes of operation for the encode inputs: the differential encode mode (Figure 3), and the single-ended encode mode (Figure 4).

The differential encode mode is recommended for sinusoidal, PECL, or LVDS encode inputs (Figure 5 and Figure 6). The encode inputs are internally biased to 1.2V through 10k equivalent resistance. The encode inputs can be taken

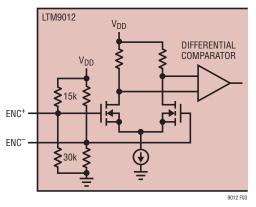
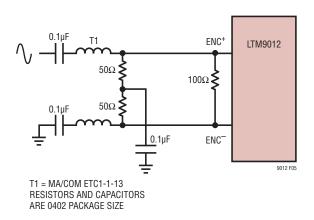


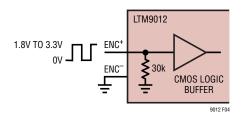
Figure 3. Equivalent Encode Input Circuit for Differential Encode Mode





above V_{DD} (up to 3.6V), and the common mode range is from 1.1V to 1.6V. In the differential encode mode, ENC⁻ should stay at least 200mV above ground to avoid falsely triggering the single-ended encode mode. For good jitter performance ENC⁺ should have fast rise and fall times.

The single-ended encode mode should be used with CMOS encode inputs. To select this mode, ENC⁻ is connected to ground and ENC⁺ is driven with a square wave encode input. ENC⁺ can be taken above V_{DD} (up to 3.6V) so 1.8V to 3.3V CMOS logic levels can be used. The ENC⁺ threshold is 0.9V. For good jitter performance ENC⁺ should have fast rise and fall times.





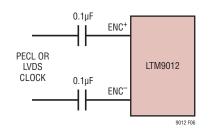


Figure 6. PECL or LVDS Encode Drive

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TLINEAR

Clock PLL and Duty Cycle Stabilizer

The encode clock is multiplied by an internal phase-locked loop (PLL) to generate the serial digital output data. If the encode signal changes frequency or is turned off, the PLL requires $25\mu s$ to lock onto the input clock.

A clock duty cycle stabilizer circuit allows the duty cycle of the applied encode signal to vary from 30% to 70%. In the serial programming mode it is possible to disable the duty cycle stabilizer, but this is not recommended. In the parallel programming mode the duty cycle stabilizer is always enabled.

DIGITAL OUTPUTS

The digital outputs of the LTM9012 are serialized LVDS signals. Each channel outputs two bits at a time (2-lane mode). At lower sampling rates there is a one bit per channel option (1-lane mode). The data can be serialized with 16-, 14-, or 12-bit serialization (see the Timing Diagrams for details). Note that with 12-bit serialization the two LSBs are not available—this mode is included for compatibility with potential 12-bit versions of these parts.

The output data should be latched on the rising and falling edges of the data clock out (DCO). A data frame output

(FR) can be used to determine when the data from a new conversion result begins. In the 2-lane, 14-bit serialization mode, the frequency of the FR output is halved.

The maximum serial data rate for the data outputs is 1Gbps, so the maximum sample rate of the ADC will depend on the serialization mode as well as the speed grade of the ADC (see Table 1). The minimum sample rate for all serialization modes is 5Msps.

By default the outputs are standard LVDS levels: 3.5mA output current and a 1.25V output common mode voltage. An external 100Ω differential termination resistor is required for each LVDS output pair. The termination resistors should be located as close as possible to the LVDS receiver.

The outputs are powered by $\ensuremath{\text{OV}_{\text{DD}}}$ which is isolated from the A/D core power.

Programmable LVDS Output Current

The default output driver current is 3.5mA. This current can be adjusted by control register A2 in the serial programming mode. Available current levels are 1.75mA, 2.1mA, 2.5mA, 3mA, 3.5mA, 4mA and 4.5mA. In the parallel programming mode the SCK pin can select either 3.5mA or 1.75mA.

Table 1. Maximum Sampling Frequency for All Serialization Modes. The Sampling Frequency for Potential Slower Speed Grades Cannot Exceed f_{SAMPLE(MAX)}.

SERIA	LIZATION MODE	MAXIMUM SAMPLING Frequency, f _s (MHz)	DCO FREQUENCY	FR FREQUENCY	SERIAL DATA RATE
2-Lane	16-Bit Serialization	125	4 • f _S	f _S	8 • f _S
2-Lane	14-Bit Serialization	125	3.5 ∙ f _S	0.5 • f _S	7 • f _S
2-Lane	12-Bit Serialization	125	3 • f _S	f _S	6 • f _S
1-Lane	16-Bit Serialization	62.5	8 • f _S	f _S	16 • f _S
1-Lane	14-Bit Serialization	71.4	7 • f _S	f _S	14 • f _S
1-Lane	12-Bit Serialization	83.3	6 • f _S	f _S	12 • f _S



Optional LVDS Driver Internal Termination

In most cases using just an external 100Ω termination resistor will give excellent LVDS signal integrity. In addition, an optional internal 100Ω termination resistor can be enabled by serially programming mode control register A2. The internal termination helps absorb any reflections caused by imperfect termination at the receiver. When the internal termination is enabled, the output driver current is doubled to maintain the same output voltage swing. In the parallel programming mode the SDO pin enables internal termination. Internal termination should only be used with 1.75mA, 2.1mA or 2.5mA LVDS output current modes.

DATA FORMAT

Table 2 shows the relationship between the analog input voltage and the digital data output bits. By default the output data format is offset binary. The 2's complement format can be selected by serially programming mode control register A1.

Table 2. Output Codes vs Input Voltage				
CH <i>n</i> + TO CH <i>n</i> -	D13 TO DO	D13 TO DO		
(0.2V RANGE)	(OFFSET BINARY)	(2's COMPLEMENT)		
>0.1000000V +0.0999878V +0.0999756V	11 1111 1111 1111 11 1111 1111 1111 11 1111 1111 1111 11 1111 1111 1110	01 1111 1111 1111 01 1111 1111 1111 01 1111 1111 1111 01 1111 1111 1110		
+0.0000122V	10 0000 0000 0001	00 0000 0000 0001		
+0.0000000V	10 0000 0000 0000	00 0000 0000 0000		
-0.0000122V	01 1111 1111 1111	11 1111 1111 1111		
-0.0000244V	01 1111 1111 1111	11 1111 1111 1110		
-0.0999878V	00 0000 0000 0000	10 0000 0000 0001		
-0.1000000V	00 0000 0000 0000	10 0000 0000 0000		
<-0.1000000V	00 0000 0000 0000	10 0000 0000 0000		

Table 2. Output Codes vs Input Voltage

Digital Output Randomizer

Interference from the A/D digital outputs is sometimes unavoidable. Digital interference may be from capacitive or inductive coupling or coupling through the ground plane. Even a tiny coupling factor can cause unwanted tones in the ADC output spectrum. By randomizing the digital output before it is transmitted off chip, these unwanted tones can be randomized which reduces the unwanted tone amplitude.

The digital output is randomized by applying an exclusive-OR logic operation between the LSB and all other data output bits. To decode, the reverse operation is applied —an exclusive-OR operation is applied between the LSB and all other bits. The FR and DCO outputs are not affected. The output randomizer is enabled by serially programming mode control register A1.

Digital Output Test Pattern

To allow in-circuit testing of the digital interface to the A/D, there is a test mode that forces the A/D data outputs (D13-D0) of all channels to known values. The digital output test patterns are enabled by serially programming mode control registers A3 and A4. When enabled, the test patterns override all other formatting modes: 2's complement and randomizer.

Output Disable

The digital outputs may be disabled by serially programming mode control register A2. The current drive for all digital outputs including DCO and FR are disabled to save power or enable in-circuit testing. When disabled the common mode of each output pair becomes high impedance, but the differential impedance may remain low.



Sleep and Nap Modes

The A/D may be placed in sleep or nap modes to conserve power. In sleep mode the entire chip is powered down, resulting in 3mW power consumption. Sleep mode is enabled by mode control register A1 (serial programming mode), or by SDI (parallel programming mode). The amount of time required to recover from sleep mode depends on the size of the bypass capacitors on V_{REF} , REFH, and REFL. For the internal capacitor values and no additional external capacitance, the A/D will stabilize after 2ms.

In nap mode any combination of A/D channels can be powered down while the internal reference circuits and the PLL stay active, allowing faster wakeup than from sleep mode. Recovering from nap mode requires at least 100 clock cycles. If the application demands very accurate DC settling then an additional 50µs should be allowed so the on-chip references can settle from the slight temperature shift caused by the change in supply current as the A/D leaves nap mode. Nap mode is enabled by mode control register A1 in the serial programming mode.

Driver Amplifier Shutdown (SHDN)

The ADC drivers may be placed in shutdown mode to conserve power independently from the ADC core. Each ADC driver has an independent SHDN pin but it is expected that all four will be tied together.

DEVICE PROGRAMMING MODES

The operating modes of the LTM9012 can be programmed by either a parallel interface or a simple serial interface. The serial interface has more flexibility and can program all available modes. The parallel interface is more limited and can only program some of the more commonly used modes.

Parallel Programming Mode

To use the parallel programming mode, PAR/SER should be tied to V_{DD} . The \overline{CS} , SCK, SDI and SDO pins are binary logic inputs that set certain operating modes. These pins can be tied to V_{DD} or ground, or driven by 1.8V, 2.5V, or 3.3V CMOS logic. When used as an input, SDO should be driven through a 1k series resistor. Table 3 shows the modes set by \overline{CS} , SCK, SDI and SDO.

Table 3. Parallel Programming Mode Control Bits (PAR/ $\overline{\text{SER}} = V_{DD}$)

(
PIN	DESCRIPTION				
CS	2-Lane/1-Lane Selection Bit 0 = 2-Lane, 16-Bit Serialization Output Mode 1 = 1-Lane, 14-Bit Serialization Output Mode				
SCK	LVDS Current Selection Bit 0 = 3.5mA LVDS Current Mode 1 = 1.75mA LVDS Current Mode				
SDI	Power Down Control Bit 0 = Normal Operation 1 = Sleep Mode				
SDO	Internal Termination Selection Bit 0 = Internal Termination Disabled 1 = Internal Termination Enabled				

Serial Programming Mode

To use the serial programming mode, PAR/SER should be tied to ground. The CS, SCK, SDI and SDO pins become a serial interface that program the A/D mode control registers. Data is written to a register with a 16-bit serial word. Data can also be read back from a register to verify its contents.

Serial data transfer starts when $\overline{\text{CS}}$ is taken low. The data on the SDI pin is latched at the first 16 rising edges of SCK. Any SCK rising edges after the first 16 are ignored. The data transfer ends when $\overline{\text{CS}}$ is taken high again.

The first bit of the 16-bit input word is the R/\overline{W} bit. The next seven bits are the address of the register (A6:A0). The final eight bits are the register data (D7:D0).

If the R/\overline{W} bit is low, the serial data (D7:D0) will be written to the register set by the address bits (A6:A0). If the R/\overline{W} bit is high, data in the register set by the address bits (A6:A0) will be read back on the SDO pin (see the Timing Diagrams sections). During a read back command the register is not updated and data on SDI is ignored.



The SDO pin is an open-drain output that pulls to ground with a 200Ω impedance. If register data is read back through SDO, an external 2k pull-up resistor is required. If serial data is only written and read back is not needed, then SDO can be left floating and no pull-up resistor is needed. Table 4 shows a map of the mode control registers.

Software Reset

If serial programming is used, the mode control registers should be programmed as soon as possible after the power supplies turn on and are stable. The first serial command must be a software reset which will reset all register data bits to logic 0. To perform a software reset, bit D7 in the reset register is written with a logic 1. After the reset is complete, bit D7 is automatically set back to zero.

Table 4. Serial Programming Mode Register Map (PAR/SER = GND) REGISTER A0: RESET REGISTER (ADDRESS 00h) WRITE ONLY

D7	D6	D5	D4	D3	D2	D1	D0
RESET	Х	Х	Х	Х	Х	Х	Х
Bit 7	RESET		Software Reset Bi	t			
	0 = Not Used						
	1 = Software Reset. All mode control registers are reset to 00h. The ADC is momentarily placed in Sleep mode.						
	This bit is automatically set back to zero at the end of the SPI Write command. The Reset register is Write only.						
	Data read back from the reset register will be random.						
Bits 6-0	Unused, Don't Care Bits.						

REGISTER A1: FORMAT AND POWER-DOWN REGISTER (ADDRESS 01h with \overline{CS} = GND)

D7	D6	D5	D4	D3	D2	D1	D0
DCSOFF	RAND	TWOSCOMP	SLEEP	NAP_4	NAP_3	NAP_2	NAP_1
				o			
Bit 7	DCSOFF		Clock Duty Cycle	Stabilizer Bit			
	0 = Clock Duty Cy	cle Stabilizer On					
	1 = Clock Duty Cy	cle Stabilizer Off. Thi	s is not recomme	nded.			
Bit 6	RAND Data Outpu	t Randomizer Mode	Control Bit				
	0 = Data Output R	andomizer Mode Off					
	1 = Data Output R	andomizer Mode On					
Bit 5	TWOSCOMP		Two's Compleme	nt Mode Control Bit	t		
	0 = Offset Binary I	Data Format					
	1 = Two's Complei	ment Data Format					
Bits 4-0	SLEEP: NAP_X		Sleep/Nap Mode	Control Bits			
	00000 = Normal C	peration					
	0XXX1 = Channel	1 in Nap Mode					
	0XX1X = Channel	2 in Nap Mode					
	0X1XX = Channel	3 in Nap Mode					
	01XXX = Channel	4 in Nap Mode					
	1XXXX = Sleep Mo	ode. Channels 1, 2, 3	and 4 are Disable	ed			
		ation of these chann					



REGISTER A2: OUTPUT MODE REGISTER (ADDRESS 02h)

D7	D6	D5	D4	D3	D2	D1	D0		
ILVDS2	ILVDS1	ILVDS0	TERMON	OUTOFF	OUTMODE2	OUTMODE1	OUTMODE0		
Bits 7-5	ILVDS2:ILVDS0		LVDS Output Cur	rent Rits					
		S Output Driver Cur							
	001 = 4.0mA LVDS Output Driver Current								
	010 = 4.5mA LVDS Output Driver Current								
	011 = Not Used								
	100 = 3.0mA LVDS	S Output Driver Cur	rent						
	101 = 2.5mA LVDS	S Output Driver Cur	rent						
	110 = 2.1mA LVDS	S Output Driver Cur	rent						
	111 = 1.75mA LVD	S Output Driver Cu	irrent						
Bit 4	TERMON		LVDS Internal Ter	mination Bit					
	0 = Internal Termir	nation Off							
	1 = Internal Termir be used with 1.75r	nation On. LVDS Ou mA, 2.1mA or 2.5m	tput Driver Current A LVDS output cur	is 2× the Current rent modes.	Set by ILVDS2:ILVD	S0. Internal termir	nation should only		
Bit 3	OUTOFF		Output Disable Bi	t					
	0 = Digital Outputs								
	1 = Digital Outputs								
Bits 2-0	OUTMODE2:OUTM		Digital Output Mo	de Control Bits					
	000 = 2-Lanes, 16								
	001 = 2-Lanes, 14								
	010 = 2-Lanes, 12	-Bit Serialization							
	011 = Not Used								
	100 = Not Used								
	101 = 1-Lane, 14-Bit Serialization								
	110 = 1-Lane, 12-Bit Serialization								
	111 = 1-Lane, 16-	Bit Serialization							
REGISTER A3: TES	ST PATTERN MSB REG	ISTER (ADDRESS (13h)						
D7	D6	D5	D4	D3	D2	D1	D0		
OUTTEST	Х	TP13	TP12	TP11	TP10	TP9	TP8		
Bit 7	OUTTEST		Digital Output Tea	st Pattern Control	Bit				
·	0 = Digital Output	Test Pattern Off	g						
	1 = Digital Output								
Bit 6	Unused, Don't Car								
Bit 5-0	TP13:TP8		Test Pattern Data	Bits (MSB)					

TP13:TP8 Set the Test Pattern for Data Bit 13(MSB) Through Data Bit 8.

REGISTER A4: TEST PATTERN LSB REGISTER (ADDRESS 04h) D7 D6 D5 D4 D3 D2 D1 D0 TP7 TP6 TP5 TP4 TP3 TP2 TP1 TP0

Bit 7-0	TP7:TP0	Test Pattern Data Bits (LSB)
	TP7:TP0 Set the Test Pattern for Data	Bit 7 Through Data Bit 0(LSB).





9012f

GROUNDING AND BYPASSING

The LTM9012 requires a printed circuit board with a clean unbroken ground plane. A multilayer board with an internal ground plane in the first layer beneath the ADC is recommended. Layout for the printed circuit board should ensure that digital and analog signal lines are separated as much as possible. In particular, care should be taken not to run any digital track alongside an analog signal track or underneath the ADC.

Bypass capacitors are integrated inside the package; additional capacitance is optional.

The analog inputs, encode signals, and digital outputs should not be routed next to each other. Ground fill and grounded vias should be used as barriers to isolate these signals from each other.

LAYOUT RECOMMENDATIONS

The pin assignments of the LTM9012 allow a flow-through layout that makes it possible to use multiple parts in a small area when a large number of ADC channels are required. The LTM9012 has similar layout rules to other BGA packages. The layout can be implemented with 6mil blind vias and 5mil traces. The pinout has been designed to minimize the space required to route the analog and digital traces. The analog and digital traces can essentially be routed within the width of the package. This allows multiple packages to be located close together for high channel count applications. Trace lengths for the analog inputs and digital outputs should be matched as well as possible. Table 5 lists the trace lengths for the analog inputs and digital outputs inside the package from the die pad to the package pad. These should be added to the PCB trace lengths for best matching.

Figures 7 through Figure 11 show an example of a good PCB layout.

HEAT TRANSFER

Most of the heat generated by the LTM9012 is transferred from the die through the bottom side of the package through numerous ground pins onto the printed circuit board. For good electrical and thermal performance, these pins should be connected to the internal ground planes by an array of vias.



Table 5. Internal Trace Lengths

PIN	NAME	(mm)
Q9	01A ⁻	0.535
Q10	01A ⁺	0.350
R11	01B ⁻	2.185
R12	01B ⁺	2.216
R9	02A ⁻	0.174
R10	02A+	0.667
S11	02B ⁻	2.976
S12	02B ⁺	2.972
S2	03A-	3.033
S3	03A+	3.031
R4	03B-	0.752
R5	03B ⁺	0.370
R2	04A-	2.130
R3	04A+	2.125
Q4	04B ⁻	0.332
Q5	04B+	0.527
A12	CH1 [−]	7.741
A11	CH1+	7.723
A9	CH2 ⁻	4.632
A8	CH2+	4.629
A6	CH3-	3.987
A5	CH3+	3.988
A3	CH4 ⁻	7.892
A2	CH4+	7.896
P1	CLK-	3.317
N1	CLK+	3.325
P4	CS	0.241
S9	DCO-	1.912
S10	DCO+	1.927
S4	FR ⁻	2.097
S5	FR ⁺	2.082
P10	PAR/SER	0.226
P5	SCK	1.553
P9	SD0	0.957
P3	SDI	1.184

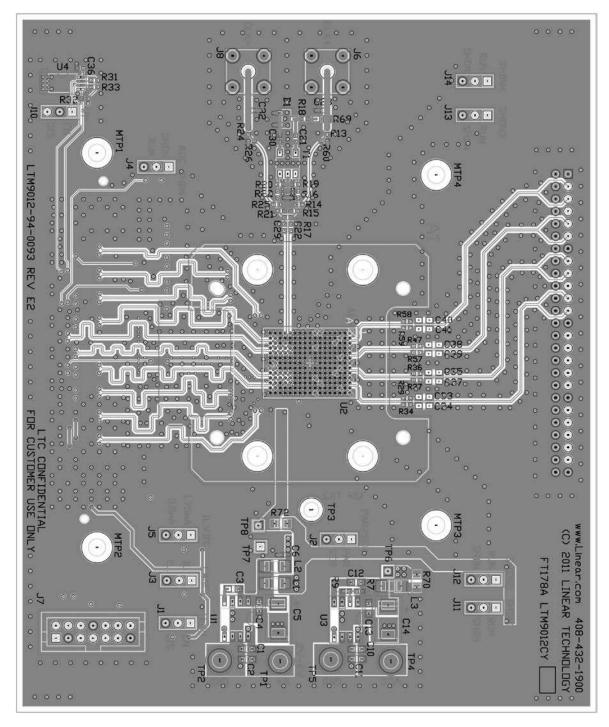


Figure 7. Layer 1 Component Side



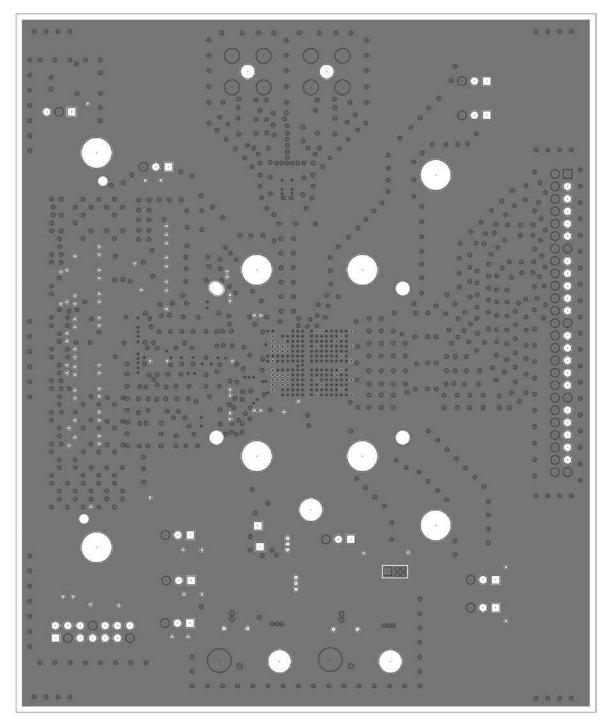


Figure 8. Layer 2



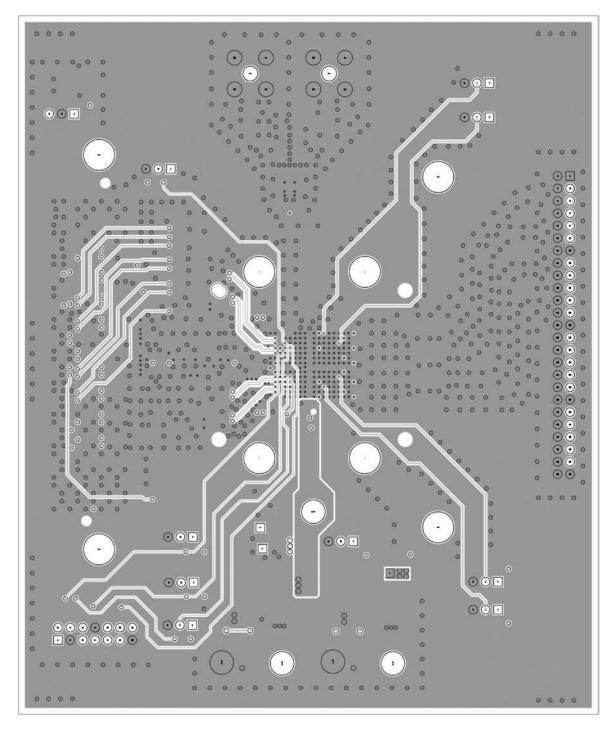


Figure 9. Layer 3



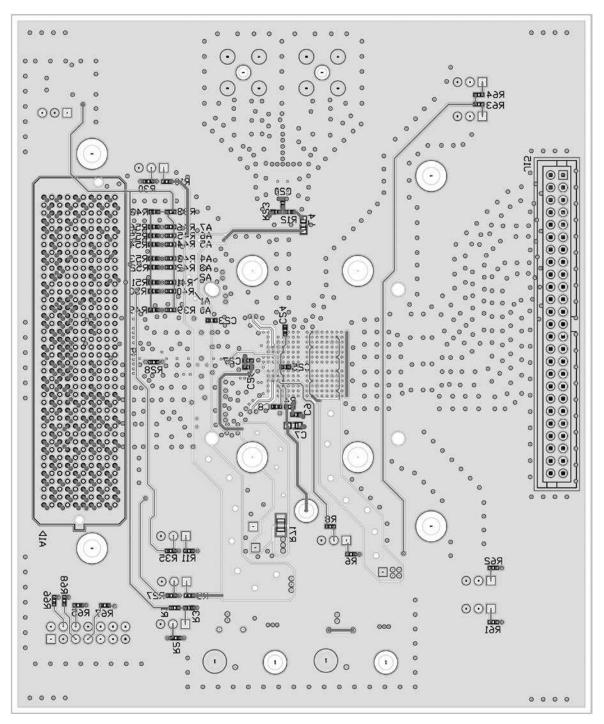
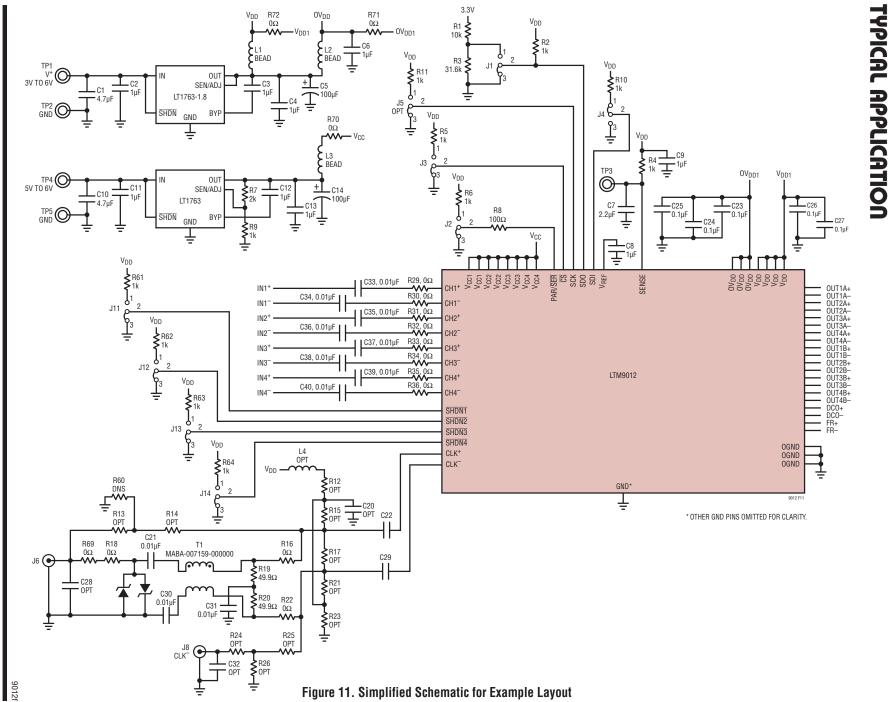


Figure 10. Back Side





LTM9012

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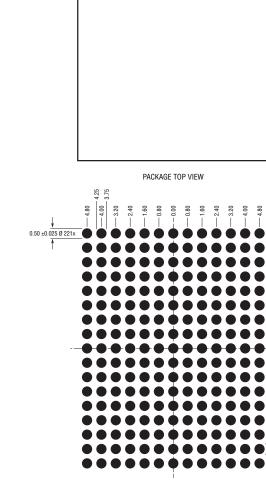
9012



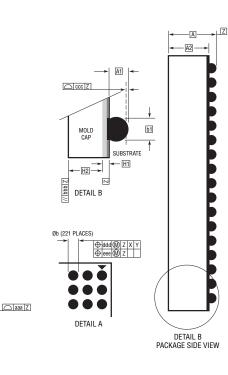
🛆 aaa Z

PIN "A1"

CORNER 4







BGA Package

221-Lead (15mm × 11.25mm × 2.82mm) (Reference LTC DWG # 05-08-1886 Rev Ø)

+Y_X

D

6.40

5.60

- 3.20

2.40

0.80 0.00

1.60 - 2.40

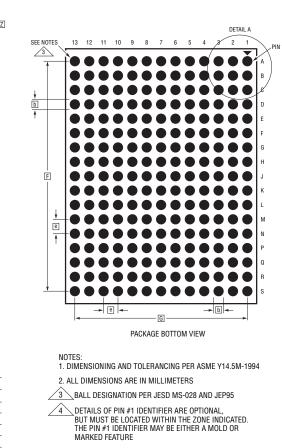
3.20

4.80

- 5.60 - 5.85 - 6.40

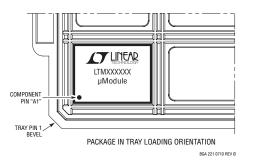
Ε

DIMENSIONS					
SYMBOL	MIN	NOM	MAX	NOTES	
Α	2.67	2.82	2.97		
A1	0.35	0.40	0.45		
A2	2.32	2.42	2.52		
b	0.45	0.50	0.55		
b1	0.45	0.50	0.55		
D		15.0			
E		11.25			
е	0.80				
F	12.80				
G	9.60				
H1	0.37	0.42	0.47		
H2	1.95	2.00	2.05		
aaa			0.15		
bbb		0.10			
CCC			0.12		
ddd			0.15		
eee			0.08		
	TOTAL NU	MBER OF B	ALLS: 221		



5. PRIMARY DATUM -Z- IS SEATING PLANE

6. SOLDER BALL COMPOSITION CAN BE 96.5% Sn/3.0% Ag/0.5% Cu OR Sn Pb EUTECTIC



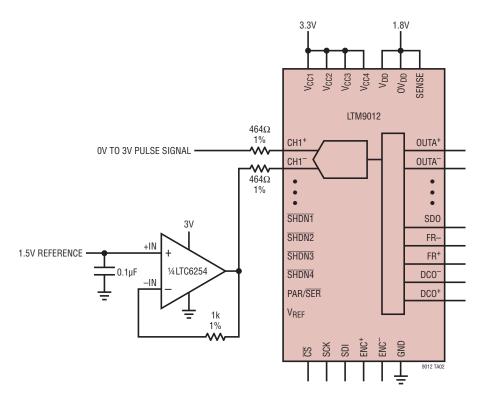
PACKAGE J **ESCRIPTION**

Please refer to http://www.linear.com/designtools/packaging/ for the most recent package drawings.



TYPICAL APPLICATION

Single-Ended Drive with Unity Gain Example



RELATED PARTS

PART NUMBER	DESCRIPTION	COMMENTS
LTC2170-14/LTC2171-14/ LTC2172-14	14-Bit, 25Msps/40Msps/65Msps 1.8V Quad ADCs, Ultralow Power	178mW/234mW/360mW, 73.4dB SNR, 85dB SFDR, Serial LVDS Outputs, 7mm × 8mm QFN-52
LTC2173-14/LTC2174-14/	14-Bit, 80Msps/105Msps/125Msps	376mW/450mW/558mW, 73.4 dB SNR, 88dB SFDR, Serial LVDS Outputs,
LTC2175-14	1.8V Quad ADCs, Ultralow Power	7mm × 8mm QFN-52
LTC2263-14/LTC2264-14/	14-Bit, 25Msps/40Msps/65Msps	99mW/126mW/191mW, 73.4dB SNR, 85dB SFDR, Serial LVDS Outputs,
LTC2265-14	1.8V Dual ADCs, Ultralow Power	6mm × 6mm QFN-40
LTC2266-14/LTC2267-14/	14-Bit, 80Msps/105Msps/125Msps	216mW/250mW/293mW, 73.4dB SNR, 85dB SFDR, Serial LVDS Outputs,
LTC2268-14	1.8V Dual ADCs, Ultralow Power	6mm × 6mm QFN-40
LTM9009-14/LTM9010-14/ LTM9011-14	14-Bit, 80Msps/105Msps/125Msps 1.8V Octal ADCs, Ultralow Power	752mW/900mW/1116mW, 73.1dB SNR, 88dB SFDR, Serial LVDS Outputs, 11.25mm × 9mm BGA-140



